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L9 and L10	10

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DB=PGPB,USPT,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

L11 19 and 110

10 L11

L10 ('6941420' '6021509' '20020087822' '6336164' '20050172082' '6490664' '5734861'
'5933840' '20020118582' '5551003')!.ABPN1,NRPN,PN,TBAN,WKU.

19 L10

L9 16 and L8

24 L9

<u>L8</u>	l3 near4 l5	42	<u>L8</u>
<u>L7</u>	l3 near4 l5L6	0	<u>L7</u>
<u>L6</u>	l2 near4 l5	92	<u>L6</u>
<u>L5</u>	lru or (least adj recently adj used)	7466	<u>L5</u>
<u>L4</u>	destag\$ or (writ\$ near3 disk)	62296	<u>L4</u>
<u>L3</u>	clean	566162	<u>L3</u>
<u>L2</u>	dirty	48469	<u>L2</u>
<u>L1</u>	711/136.ccls.	436	<u>L1</u>

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- [#3](#) (destag* dirty<IN>metadata)
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- [#5](#) (destag* dirty<IN>metadata)
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- [#7](#) (least recently used<in>metadata)
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